Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/036,922	FECHER ET AL.	
Examiner	Art Unit	
Dmitry Levitan	2616	

SEARCHED					
Class	Subclass	Date	Examiner		
370	357 360 366				
379	32.01		DL		
	33	1-/2	6/06		
455	455-	-/-/	/		
	457				
709	227				
	222				
		/			

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
IEEE, EAST	5/20/0	b DC	
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